Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/771,464	VANTTINEN ET AL.	
Examiner	Art Unit	
Hanh Nouven	2616	

SEARCHED				
Class	Subclass	Date	Examiner	
370	316	6/3/2006	HN	
	312			
	332			
	352			
455	456.1			
	457			
	450			
	403			
,	404.2			
	456.6			
	423			
	436			
	440			
	456.2			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
<u> </u>					

(INCLUDING SEA	I NOTES RCH STRATEGY	<u>')</u>
	DATE	EXMR
east	6/3/2006	HN